

**Search Notes**

Application/Control No.

10/790,296

Examiner

Paul Dinh

Applicant(s)/Patent under  
Reexamination

PHAN ET AL.

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	19-21	6/1/2005	PD
382	145	6/1/2005	PD
438	14, 16	6/1/2005	PD
430	5, 22, 30	6/1/2005	PD
356	401	7/16/2005	PD
above	update	9/7/2005	PD
above	update	1/9/2006	PD

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
716	4,19,21	1/9/2006	PD
430	22,30	1/9/2006	PD

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST, IEEE	6/1/2005	PD